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Siliup Semiconductor

SP40N11DNJ

40V N-Channel MOSFET

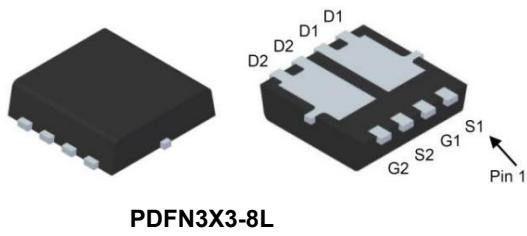
Product Summary

$V_{(BR)DSS}$	$R_{DS(on)TYP}$	I_D
40V	11mΩ@10V	22A
	14mΩ@4.5V	

Feature

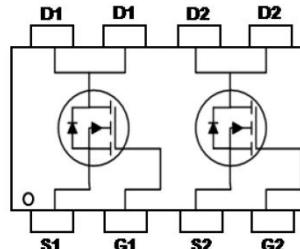
- High power and current handing capability
- Lead free product is acquired
- Surface mount package

Package

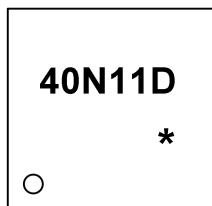


PDFN3X3-8L

Circuit diagram



Marking



40N11D =Device Code
* =Month Code



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Absolute maximum ratings (Ta=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	40	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	22	A
Pulsed Drain Current	I _{DM}	88	A
Maximum Power Dissipation	P _D	26	W
Single Pulse Avalanche Energy ¹	E _{AS}	20	mJ
Thermal Resistance,Junction-to-Ambient	R _{θJA}	4.8	°C/W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 To 150	°C

Electrical characteristics (T_A=25 °C, unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V ID=250μA	40	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =40V, V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , ID=250μA	1	1.5	2.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, ID=8A	-	11	14	mΩ
		V _{GS} =4.5V, ID=4A	-	14	20	mΩ
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =20V, V _{GS} =0V, F=1.0MHz	-	964	-	PF
Output Capacitance	C _{oss}		-	109	-	
Reverse Transfer Capacitance	C _{rss}		-	96	-	
Switching Characteristics						
Turn-on Delay Time	t _{d(on)}	VDD=20V, RL=2.5Ω VGS=10V, RGEN=3Ω	-	5.5	-	nS
Turn-on Rise Time	t _r		-	14	-	
Turn-Off Delay Time	t _{d(off)}		-	24	-	
Turn-Off Fall Time	t _f		-	12	-	
Total Gate Charge	Q _g	VDS=20V, ID=8A, VGS=10V	-	22.9	-	nC
Gate-Source Charge	Q _{gs}		-	3.5	-	
Gate-Drain Charge	Q _{gd}		-	5.3	-	
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} =0V, IS=9A	-	0.8	1.2	V

Note :

1. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
2. The EAS data shows Max. rating . The test condition is VDD=25V, VGS=10V, L=0.1mH
3. The power dissipation is limited by 150°C junction temperature



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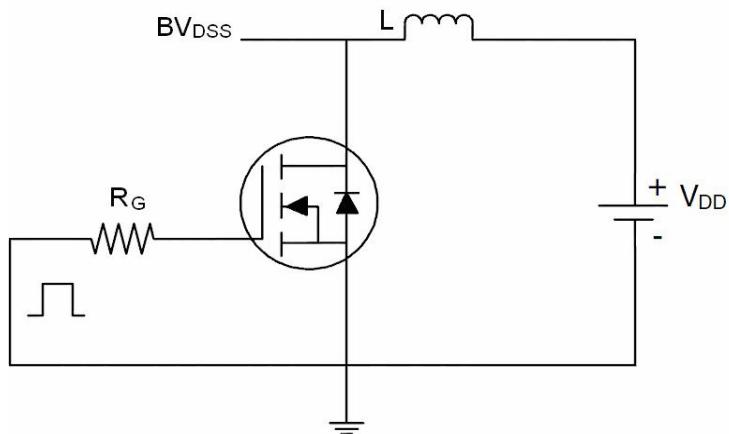
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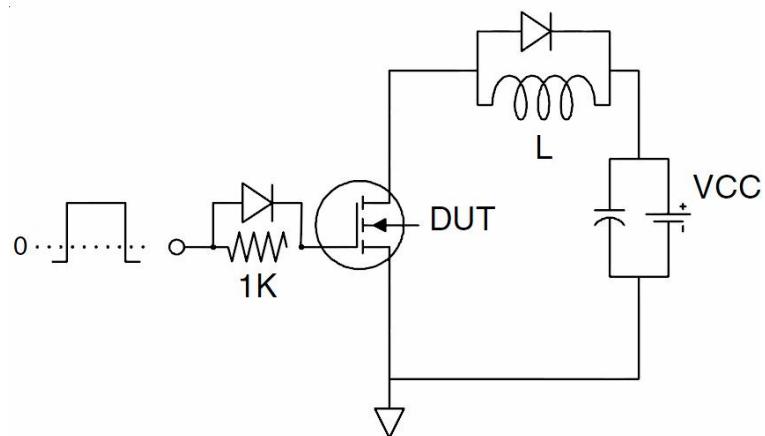
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Test Circuit

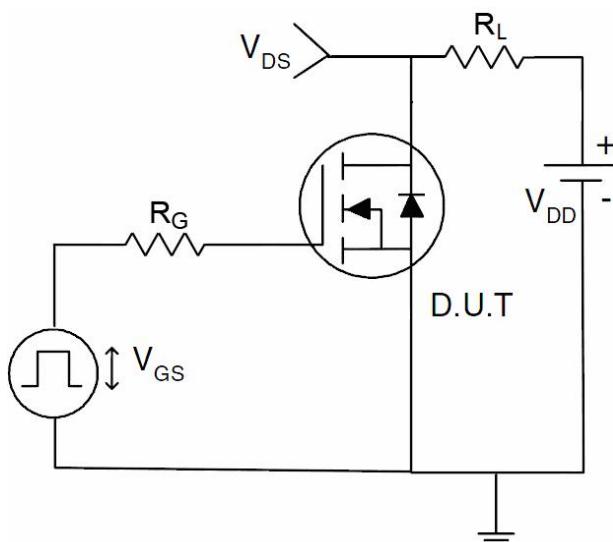
1) EAS Test Circuits



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





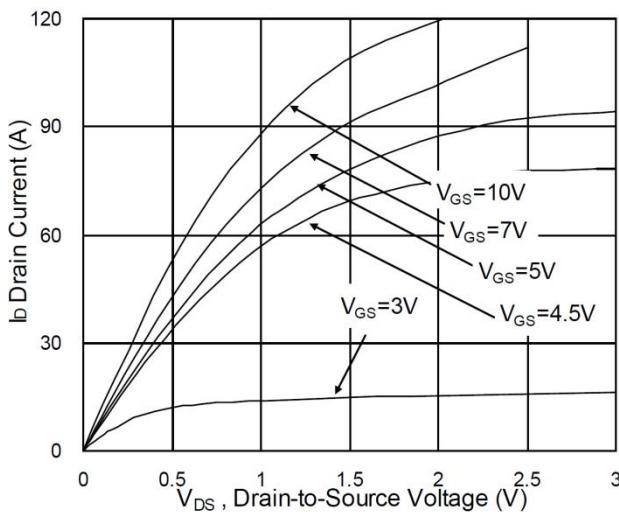
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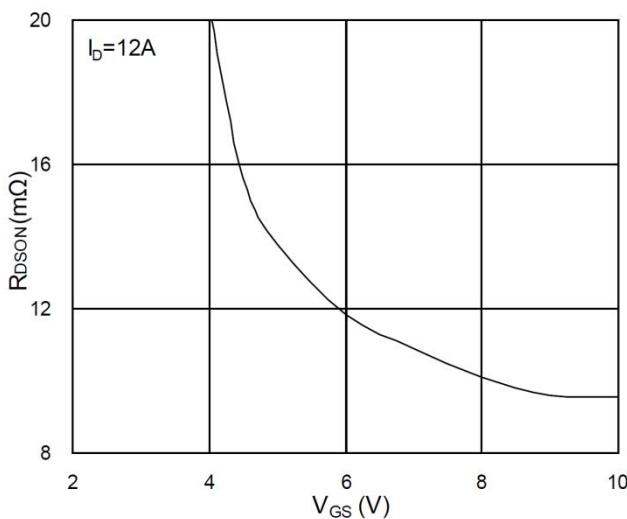
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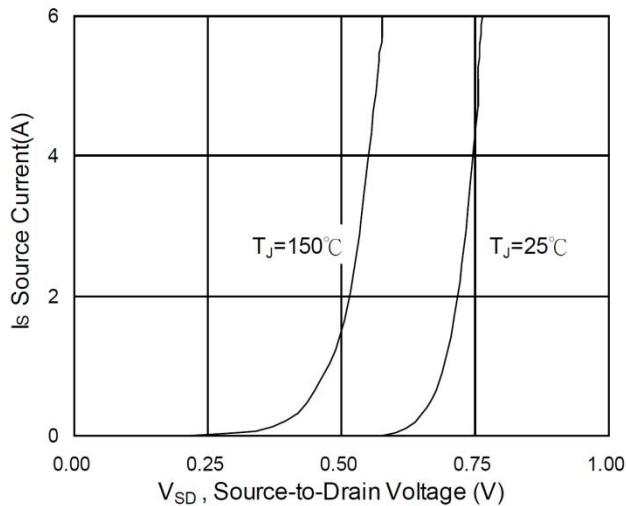
Typical Characteristics



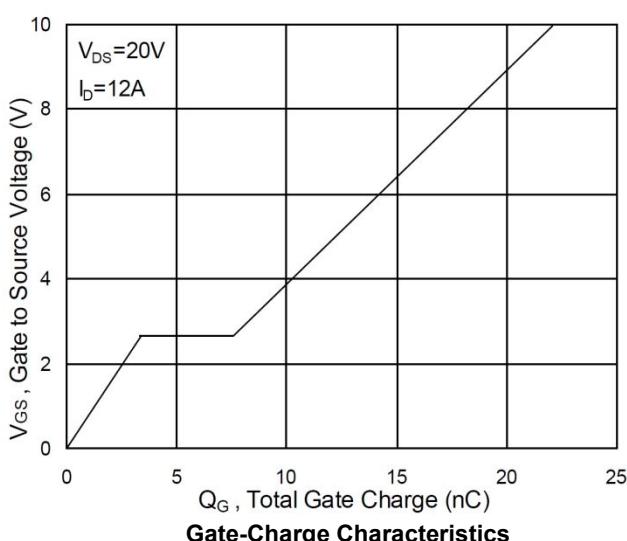
Typical Output Characteristics



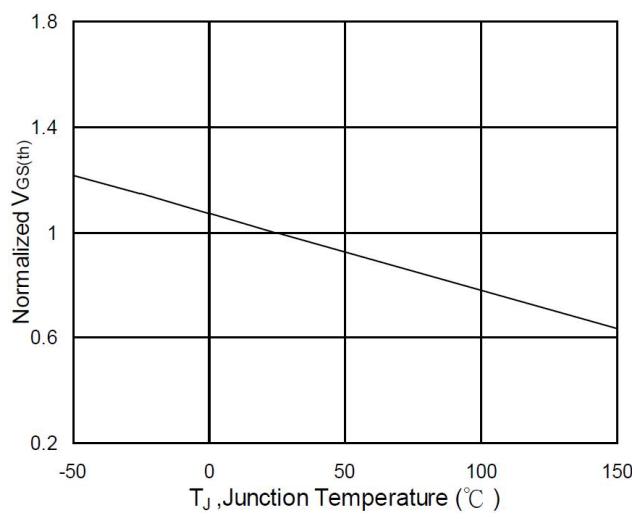
On-Resistance vs. G-S Voltage



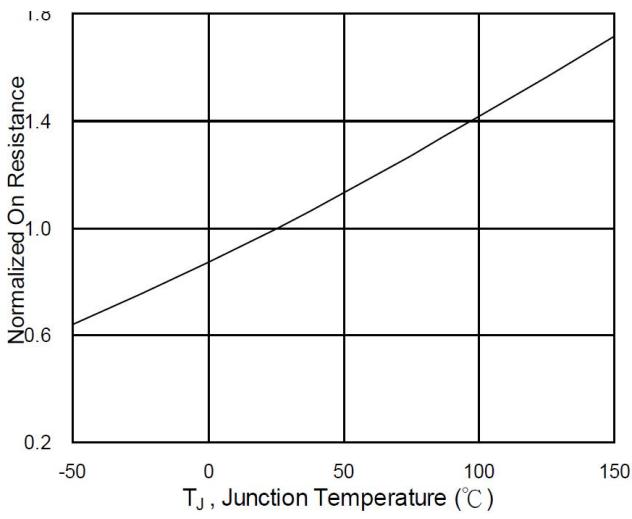
Forward Characteristics of Reverse



Gate-Charge Characteristics



$V_{GS(th)}$ vs. T_J



Normalized R_{DSON} vs. T_J

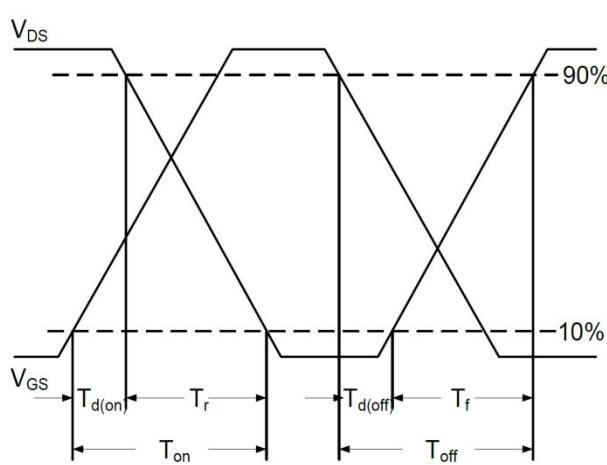
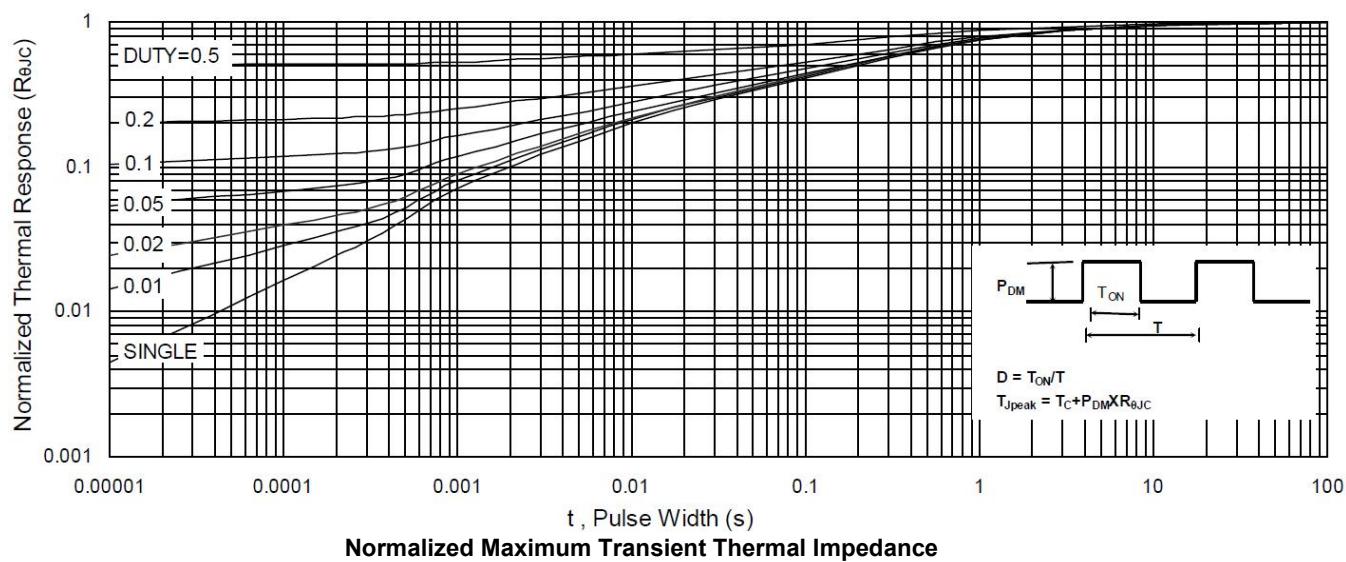
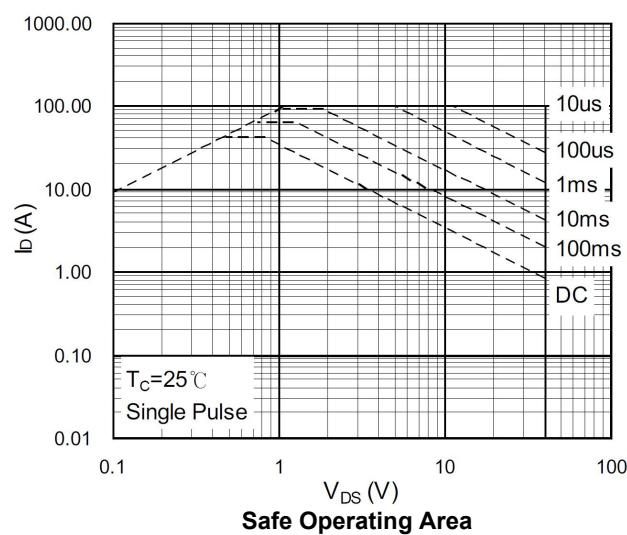
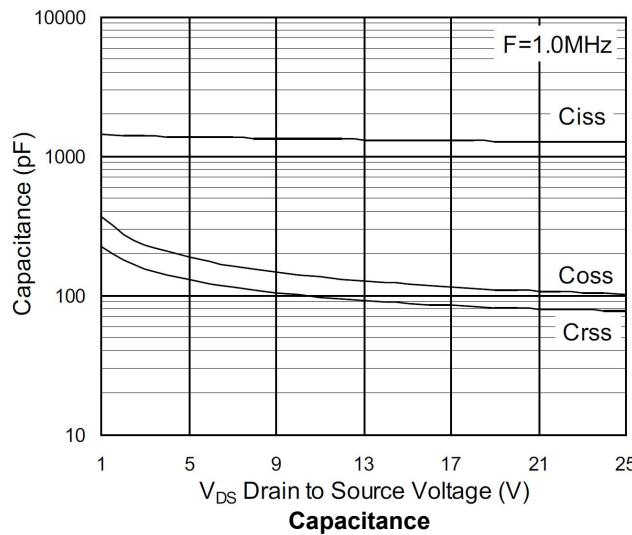


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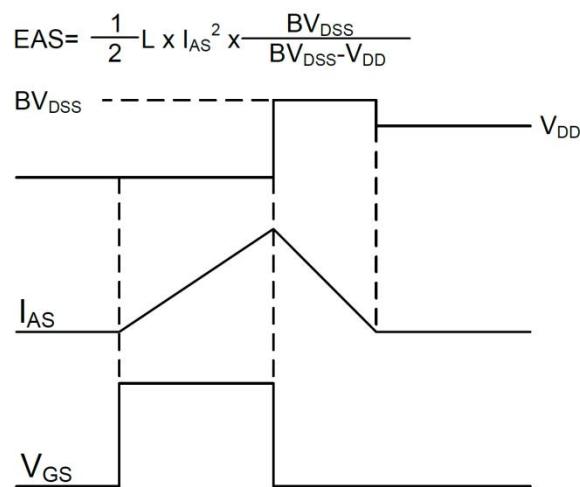
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Switching Time Waveform



Unclamped Inductive Switching Waveform

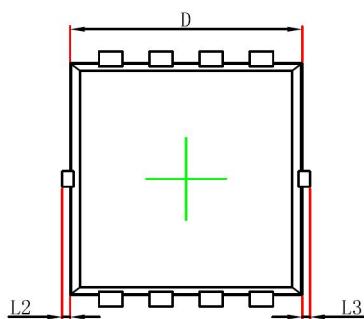


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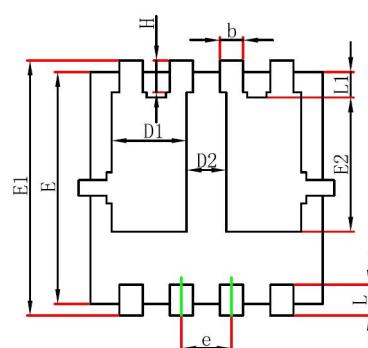
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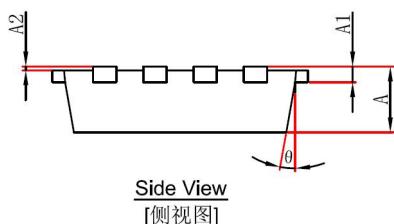
PDFNWB3.3×3.3-8L-B Package Information



Top View
[顶视图]



Bottom View
[背视图]



Side View
[侧视图]

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.			0.006 REF.
A2	0~0.05			0~0.002
D	2.900	3.100	0.114	0.122
D1	0.935	1.135	0.037	0.045
D2	0.280	0.480	0.011	0.019
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100			0~0.004
L3	0~0.100			0~0.004
H	0.315	0.515	0.012	0.020
θ	9°	13°	9°	13°